Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
09/853,770	SHIGEMATSU ET AL.	
Examiner	Art Unit	_
Fllen C. Tran	2134	

	SEARCHED				
Class	Subclass	Date	Examiner		
713	186	3/4/2006	ECT		
713	186	10/22/2006	ECT		
726	9	10/22/2006	ECT		
726	20	10/22/2006	ECT		

INT	INTERFERENCE SEARCHED		
. Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPTO, USPG, EPO, JO, DERWENT, IBM TECH DES, INVENTOR - PALM	3/4/2006	ECT		
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	10/22/2006	ECT		
NPL - IEEE XPLORE	10/22/2006	ECT		
All claims have been reviewed by Examiner for possible 101 rejections	10/22/2006	ECT		
		10.00		